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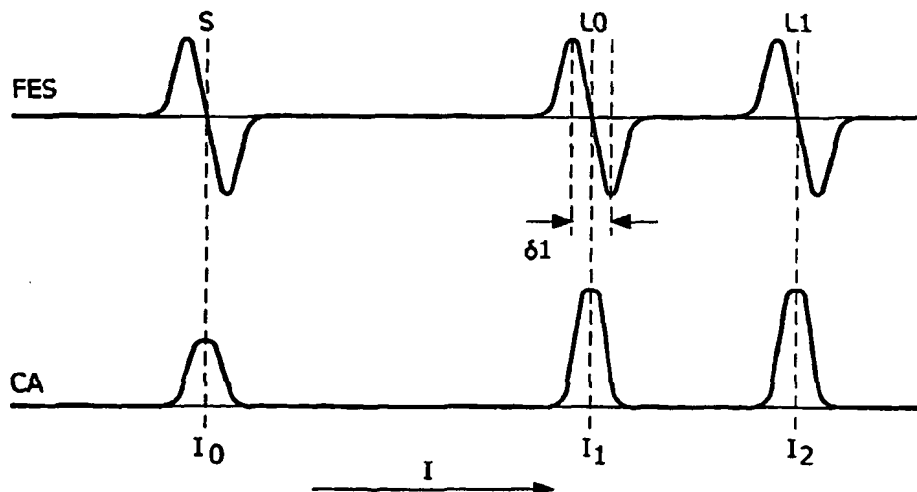
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(54) Title: METHOD AND APPARATUS FOR MEASURING THE DEPTH OF A DATA RECORD LAYER IN AN INFORMATION RECORD MEDIUM



(57) Abstract: Apparatus and method for measuring the depth of data record layers of an optical storage disc having a cover layer of thickness, an entrance surface, and, for example, a first data layer (L0), a second data layer (L1) and a third data layer. The optical apparatus comprises a spherical aberration compensator, and an objective lens mounted in an actuator. In order to provide the spherical aberration compensator with right control signal, the depth of each data layer must be measured and means are provided for measuring the depth of the data layer(s) of a single- or multi- layer disc, and this achieved by using the distance between zero-crossings of the focus error signal (FES). A proportionality constant between the actuator current and the depth of the record layer can be calculated. Oscillations of the rotating medium may be compensated.

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